

# Anomalous bias dependence of tunnel magnetoresistance in a magnetic tunnel junction

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## Abstract

We have fabricated a spin-polarized tunneling device based on half-metallic manganites incorporating  $\text{Ba}_2\text{LaNbO}_6$  as insulating barrier. An anomalous bias dependence of tunnel magnetoresistance (TMR) has been observed, the first of its kind in a symmetric electrode tunnel junction with single insulating barrier. The bias dependence of TMR shows an extremely sharp zero bias anomaly, which can be considered as a demonstration of the drastic density of states variation around the Fermi level of the half-metal. This serves as a strong evidence for the existence of minority spin tunneling states at the half-metal insulator interface.

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In recent years Magnetic Tunnel Junction (MTJ) [1] has become the subject of great interest because of the richness in physical properties it exhibits, and potential applications. It has been observed that the transport properties of MTJ depend not only on the ferromagnetic metal electrodes but also on the insulator-electrode couple and its interface and that the insulator plays a crucial role in selecting bands that can tunnel [2, 3]. However, not much thought has been given to what happens to the band structure at the interface between the half metal and the insulator in MTJs consisting of half metals. Till date there is no evidence of minority spin states in manganite tunnel junction interfaces, although there are reports of existence of minority spin states in manganites [4]. The present article establishes the presence of minority spin tunneling states in half metal near the half metal-insulator interfaces. An extremely sharp zero bias anomaly in the bias dependence of TMR has been observed.

In almost all MTJs, the Tunnel Magnetoresistance (TMR;  $R = R_{\parallel} - R_{\text{AP}} = R_{\text{AP}}$  where  $R_{\text{AP}}$ ,  $R_{\parallel}$  are the resistances in the antiparallel and parallel magnetization configuration respectively.) decreases with increasing bias voltage [1]. Several mechanisms have been proposed to explain this behaviour. For example, there are processes like spin independent two-step elastic tunneling via defect states [5] in the insulating barrier and inelastic processes like spin flip scattering by magnon excitations [6, 7], magnetic impurities [8] in the barrier etc. The effect of density of states (DOS) [9] or the influence of electric field on the barrier height is often discussed in explaining the variation of TMR at higher bias. It is believed that in the low bias region the electronic band structure of the electrodes play fundamental roles. Yet we do not observe the effect of sharp variation of electronic density of states (DOS) about the Fermi level at zero bias (for reasons to be discussed later). This report is a clear demonstration of the effect of drastic DOS variation around the Fermi level near the interface.

Here we report the transport properties of a manganite MTJ where  $\text{Ba}_2\text{LaNbO}_6$  has been introduced as the insulating barrier. The MTJ was prepared by pulsed laser deposition. The trilayer  $\text{La}_{0.67}\text{Sr}_{0.33}\text{MnO}_3$  (LSMO)/ $\text{Ba}_2\text{LaNbO}_6$  (BLNO)/LSMO was deposited on single crystalline  $\text{SrTiO}_3$  (100) substrate held at a temperature  $800^\circ\text{C}$  and the oxygen pressure was 400 mTorr. BLNO has a complex cubic perovskites structure and can be grown epitaxially on single crystal perovskite substrates [10, 11]. The thickness of the bottom LSMO layer is 1000Å and that of the top layer 500Å while the estimated thickness of

the insulating spacer from the deposition rate calibration of BLNO is 50 Å. The microfabrication in the cross-strip geometry was done using photolithography and ion-beam milling. The bottom layer was patterned using photolithography while the top electrode and the insulating layer using ion-beam milling. The junction area is  $50 \times 50 \text{ nm}^2$ . The transport and magnetoresistive properties were measured in the current perpendicular to plane geometry using four terminal method with the magnetic field applied in the plane of the sample.

The junction resistance in the absence of magnetic field shows a distinct peak at around 125 K (Fig: 1), typical of manganite tunnel junctions [12, 13]. With increase in bias level the temperature dependence of junction resistance becomes weaker (Fig: 1). The conductance curves show parabolic voltage dependence (Fig: 2). We have fitted the differential conductance vs. voltage curves using asymmetric barrier Brinkman model [15] in different voltage ranges. The average barrier height and the barrier width turns out to be in the range 0.2–0.25 eV and 32–37 Å respectively. The asymmetry in the barrier obtained from the Brinkman model is very small, about 3–4 mV only and hence the current-voltage characteristics can be well fitted with symmetric barrier Simmons model [14], producing similar results. The barrier parameters like average barrier height and barrier width are almost temperature independent within the relevant temperature range. All these observations indicate that the device is free of any pinhole shorts and tunneling is the dominant transport mechanism [16]. The highest value of TMR obtained at any bias current is around 10%. Low TMR value signifies a considerable reduction of spin polarization at the electrode-barrier interface. The tunnel magnetoresistance vanishes above 150 K, as is the case generally for manganite tunnel junctions [17].

The observed bias dependence of TMR (Fig: 3) has an unusual feature. Previous reports on bias dependence show that Tunnel Magnetoresistance decreases with increasing bias voltage and there is not much appreciable variation around zero bias [1]. Here we have observed that the TMR undergoes a sharp rise (Fig: 3) with increasing bias voltage below 20–25 mV at 6 K. Only one or two groups [2, 3, 18] have seen bias dependence like this but there are some striking differences between their observations and ours. For example, De Teresa et al. [2] observed such bias dependence in case of  $\text{Co/SrTiO}_3/\text{La}_{0.67}\text{Sr}_{0.33}\text{MnO}_3$  hybrid tunnel Junction and Sharma et al. [3] observed this in case of MTJ with composite barrier where the TMR undergoes a sharp decrease as one approaches zero bias. In all those cases highly asymmetric barrier is the key factor in the anomalous bias dependence of TMR. But here we

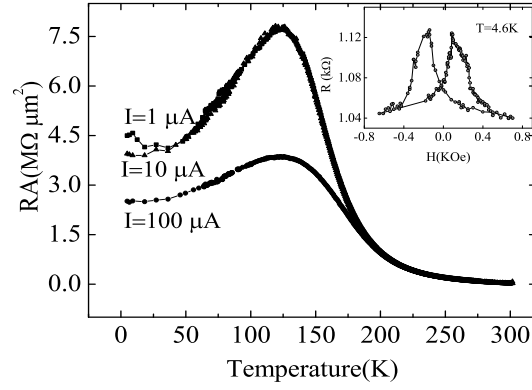


FIG . 1: Junction resistance-area product ( $RA$ ) at different bias currents in absence of magnetic field. Junction resistance shows weaker temperature dependence at higher bias current. Inset: Junction resistance vs. magnetic field at 4.6K

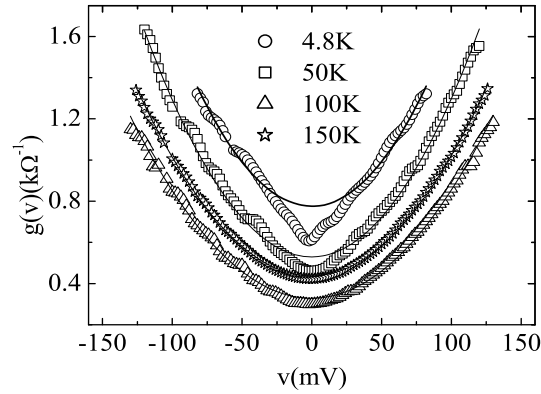


FIG . 2: Differential junction conductance vs. voltage curves at different temperatures in absence of magnetic field. The continuous lines are the Brinkman fits.

are dealing with a half metallic tunnel junction with single insulating barrier. There is a marginal asymmetry in the bias dependence. This is due to a small barrier asymmetry close to 3–4 mV which is very small compared to the average barrier height of 0.20–0.25 eV. This is manifested in the conductance minimum at low temperature (Fig: 2) being shifted with respect to zero bias.

There are several factors contributing to the bias dependence of TMR. If there exists defect sites within the barriers, creation of states either thermally or by hot electron impact

will facilitate two-step tunneling. Since these states are not polarized, the two-step tunneling is spin independent and does not contribute to TMR. With increase in bias voltage, density of available defect states increases exponentially. As a result the two-step tunneling current increases sharply with increasing bias voltage, thus reducing the TMR with increasing bias. There are other inelastic processes that can influence the bias dependence. For example "hot electrons" tunneling across the insulating barrier may lose their energy by emitting a magnon and thereby flipping the electron spin. With increasing bias more magnons can be emitted, resulting in reduced TMR. Spin flip scattering cross-section due to magnetic impurities in the barrier increases with increasing bias thus reducing the TMR. The existence of Coulomb gap due to metallic inclusions at the junction interface also reduces the TMR with increasing bias [12]. Obviously these higher order tunneling processes cannot explain the anomalous bias dependence around zero bias.

Biasing an MTJ leads to the contributions from electrons, which tunnel from the occupied states below the Fermi level of one electrode to the empty states at the same energy above the Fermi level of the other electrode. Due to the change in DOS of ferromagnets as a function of energy, the spin polarization should be voltage dependent and hence the TMR. But in practice, the nature of bias dependence in almost all MTJ's does not seem to reflect that. This is because for transition metals, although most of the spin polarization comes from d-band, majority of the tunneling electrons are from s-band which is not sharply polarized. There is no significant change of this situation if we take into account the effect of s-d hybridization [19]. On the other hand, in half-metals like manganites, the spin up and spin down bands are completely split (Fig: 4) resulting in the spin polarization being immuned to the sharp variation in DOS near the band edge. Thus the DOS variation with change in bias voltage does not affect the spin polarization.

The observed bias dependence can be interpreted as follows. Due to the perturbation caused by the complex band structure of the insulating barrier, the spin split band edges at the interfaces get modified in such a way that there is a substantial overlap of the up and down spin bands below the Fermi level (Fig: 4). This results in the introduction of minority spin states. The existence of minority spin states will bring the variation in majority spin DOS into play because then it will strongly influence the tunneling spin polarization. At low bias, the DOS for the majority spin band around Fermi level is much less than at higher voltage and the DOS slope is also much sharper at near the Fermi level. With increase

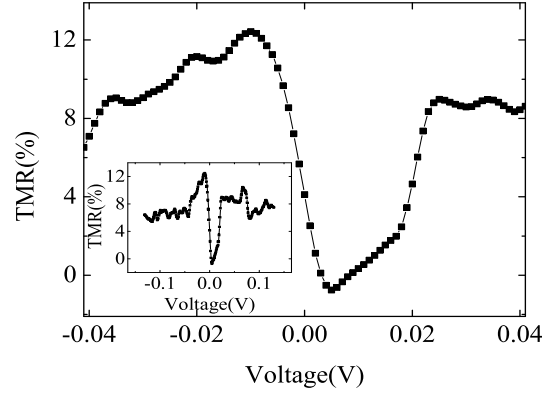


FIG . 3: Bias dependence of TMR at 6K highlighting the anomalous behaviour around zero bias.

Inset: Bias dependence in the experimental voltage range

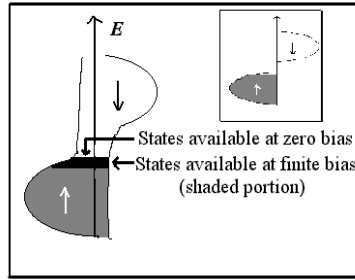


FIG . 4: Modified band structure of LSMO at the interface showing minority states around the Fermi level and the majority spin DOS increasing with increasing bias. Inset: Band structure of bulk LSMO

in bias voltage from zero value, the majority spin DOS increases sharply (Fig: 4). Hence within a certain bias window around zero bias the spin polarization can have a sharp rise with increasing bias. Still one should expect the TMR to increase beyond the observed bias range considering the large band width in LSMO (half band width 0.75eV). But at higher voltages the opening up of inelastic conduction channel is bound to have an influence on the bias dependence of TMR. Thus we get the fingerprint of the DOS profile only in the low bias range.

A small inverse TMR (where  $R_{AP} < R_P$ ) is also observed in the extreme vicinity of zero bias. Inverse TMR is expected in systems with the two different electrodes having opposite spin polarizations within a certain bias range [20]. In our case the majority and minority

spin DOS become comparable near the Fermi level at zero bias. And since there is a small relative zero bias shift of Fermi levels between the two electrodes, it may give rise to Inverse TMR near zero bias.

To summarize, we propose that the observed anomalous bias dependence of TMR can be considered as the experimental demonstration of the influence of interfacial DOS around zero bias in a symmetric MTJ and that the influence of the insulating barrier can lead to the formation of minority spin tunneling DOS at the interfaces of a half-metallic tunnel junction.

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- [1] J. S. Moodera, Lisa R. Kinder, Terrilyn M. Wong, R. Meserve, *Phys. Rev. Lett.* 74 3273 (1995)
  - [2] J. M. De Teresa, A. Barthelémy, A. Fert, J. P. Contour, F. Montaigne, P. Sensor, *Science* 286 507 (1999)
  - [3] Manish Sharma, Shan X. Wang, Janice H. Nickel, *Phys. Rev. Lett* 82 616 (1999)
  - [4] B. Nadgorny, I. I. Mazin, M. Osofsky, R. J. Soulen. Jr., P. Broussard, R. M. Stroud, D. J. Singh, V. G. Harris, A. Arsenov, and Ya. Mukovskii, *Phys. Rev. B* 63 184433 (2001)
  - [5] J. Jhang, R. M. White, *Jour. Appl. Phys.* 83 6512 (1999)
  - [6] J. S. Moodera, J. Nowak and Rene J. M. van de Veerdonk, *Phys. Rev. Lett.* 80 2941 (1998)
  - [7] S. Zhang, P. M. Levy, A. C. Marley, S. S. P. Parkin, *Phys. Rev. Lett.* 79 3744 (1997)
  - [8] R. Jansen, J. S. Moodera, *Jour. Appl. Phys.* 83 6682 (1998)
  - [9] X. H. Xiang, T. Zhu, J. Du, G. Landry, J. Q. Xiao *Phys. Rev. B* 66 174407 (2002)
  - [10] S. P. Pai, J. Jasudasan, P. R. Apte, R. Pinto, J. Kurian, P. K. Sajith, J. James, J. Koshy, *Physica C* 290 105 (1997)
  - [11] J. Kurian, H. K. Varma, J. Koshy, S. P. Pai, R. Pinto, *Appl. Phys. Lett.* 69 2909 (1996)
  - [12] J. Z. Sun, D. W. Abraham, K. Roche, S. S. P. Parkin, *Appl. Phys. Lett* 73 1008 (1998)
  - [13] J. Z. Sun, K. P. Roche, S. S. P. Parkin, *Phys. Rev. B* 61 11244 (2000)
  - [14] J. G. Simmons, *Jour. Appl. Phys.* 34 1793 (1963)
  - [15] W. F. Brinkman, R. C. Dynes, J. M. Rowell, *Jour. Appl. Phys.* 41 1915 (1970) ~~item~~ res J. Z. Sun, D. W. Abraham, K. Roche, S. S. P. Parkin,
  - [16] J. J. Akerman, J. M. Slaughter, R. W. Dave, I. K. Schuller, *Appl. Phys. Lett.* 79 3104 (2001)

- [17] J. Z. Sun, L. K. Rusin Elbaum, P. R. Duncombe, A. Gupta and R. B. Laibowitz Appl. Phys. Lett. 70 1769 (1997)
- [18] G. Hu, R. Chopadekar, Y. Suzuki Jour. Appl. Phys. 93 7516 (2003)
- [19] J. A. Hertz, and K. Aoi, Phys. Rev. B 8 3252 (1973)
- [20] C. Mitra, P. Raychaudhuri, K. Dorr, K. H. Müller, L. Schultz, P. M. Oppeneer and S. Wirth, Phys. Rev. Lett. 90 017202 (2003)